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Sheet 1 of

Co	Complete if Known				
Application Number	09/902,902				
Filing Date	07/29/2001				
First Named Inventor	Stephen C. Baer				
Group Art Unit	2838				
Examiner Name					
Attorney Docket Number					

U.S. PATENT DOCUMENTS

				U.S. PATENT DUCU	INEW 12	
Examiner Initials*	Cite No. ¹	t Number .	cument ind Code ² if known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
110		3,013,467		Minsky	12/1961	
000		3,513,980		Petráň et al.	6/1970	
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Ugn.		4,100,571		Dykes and Oharek	7/1978	
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Jaks 1		5,952,668		Baer	9/1999	
ToB 1		6,259,104 B	1	Baer	7/2001	
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				FORE	IGN PATENT DOCUMENTS	S		
Examiner	Cite		Foreign Patent Doo	ument	Name of Patentee or	Date of Publication of	Pages, Columns, Lines,	T
Initials	No.1	Office ³	Number ⁴	Kind Code ⁵ (<i>if known</i>)	Applicant of Cited Document	Cited Document MM-DD-YYYY	Where Relevant Passages or Relevant Figures Appear	T ⁶
010		FR	2,613,845		Maureau et al.	10/1984		1 1
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¹ Unique citation designation number. ² See attached Kinds of U.S. Patent Documents. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

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pheet 2 of 3

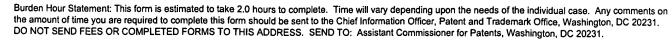
Co	mpl te if Known			
Application Number	09/902,902			
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First Named Inventor	Stephen C. Baer			
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Examiner Name		_		
Attorney Docket Number				

	OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS						
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²				
JB		S. Inoué, "Imaging of Unresolved Objects, Superresolution, and Precision of Distance Measurement with Video Microscopy" in Taylor and Wang, Fluorescence Microscopy of Living Cells in Culture, Part B San Diego, U.S.A. 1989 pp.85-112. Academic Press, Inc.					
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JB		Sheppard and Gu, "Image Formation in Two-Photon Fluorescence Microscopy" Optik vol. 86, No.3, Stuttgart, Germany 1990, pp. 104-106.					

Examiner Signature	Jack	Berman	Date Considered	7/30/03

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Cor	mplete if Known	1
Application Number	09/902,902	-
Filing Date	07/29/2001	
First Named Inventor	Stephen C. Baer	
Group Art Unit	2838	
Examiner Name		
Attorney Docket Number		

		OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS	
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T2
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Examiner Signature Jack Berman Date Considered 7/30/0	
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Signature year Considered Considered	19

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